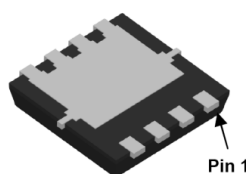
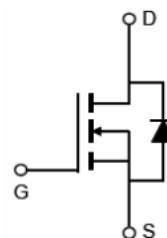


Main Product Characteristics:

V_{DSS}	30V
$R_{DS(on)}$	3.2m Ω (typ.)
I_D	35A


PRPAK 3*3

Schematic Diagram
Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature


Description:

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute max Rating:

Symbol	Parameter	Max.	Units
I_D @ TC = 25°C	Continuous Drain Current, V_{GS} @ 10V ①	35	A
I_{DM}	Pulsed Drain Current ②	120	
P_D @TC = 25°C	Power Dissipation ③	27	W
V_{DS}	Drain-Source Voltage	30	V
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}	Single Pulse Avalanche Energy	80	mJ
I_{AS}	Avalanche Current	40	A
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to +150	°C

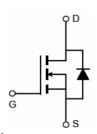
Thermal Resistance

Symbol	Characterizes	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-case ③	—	4.5	$^{\circ}C/W$
$R_{\theta JA}$	Junction-to-ambient ($t \leq 10s$) ④	—	60	$^{\circ}C/W$

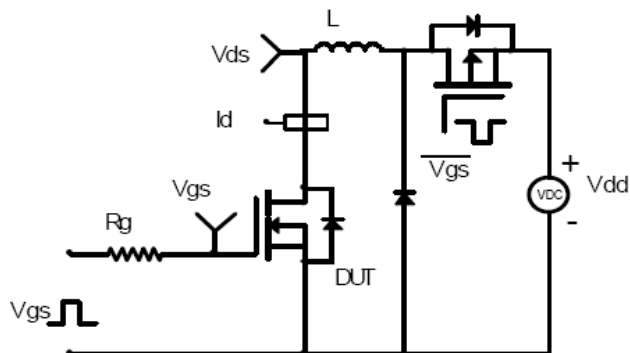
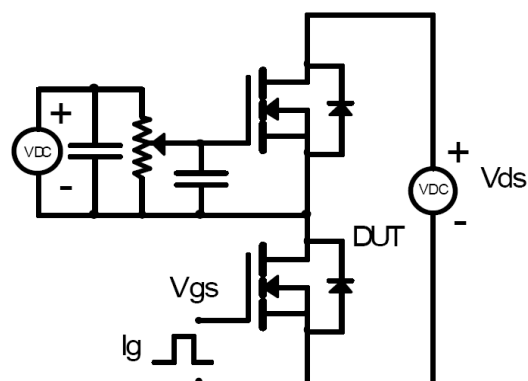
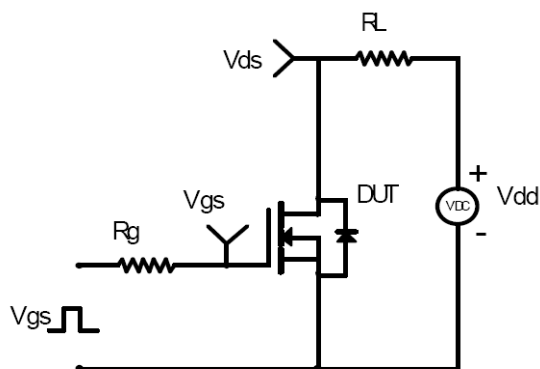
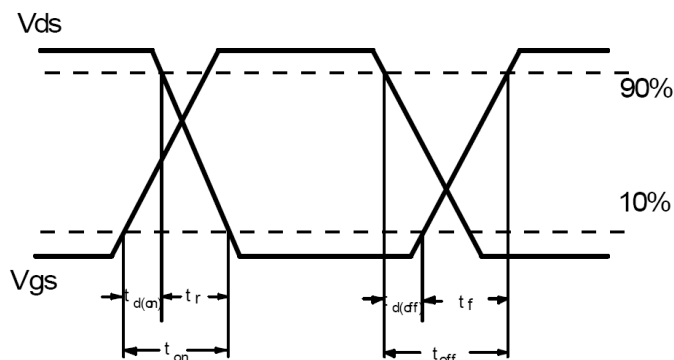
Electrical Characterizes @ $T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	30	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	3.2	3.9	m Ω	$V_{GS}=10V, I_D=20A$
		—	4.9	6.1		$V_{GS}=4.5V, I_D=15A$
$V_{GS(th)}$	Gate threshold voltage	1.2	—	2.2	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
I_{DSS}	Drain-to-Source leakage current	—	—	1	μA	$V_{DS} = 30V, V_{GS} = 0V$
I_{GSS}	Gate-to-Source forward leakage	—	—	100	nA	$V_{GS} = 20V$
		—	—	-100		$V_{GS} = -20V$
Q_g	Total gate charge	—	15	—	nC	$I_D = 20A,$ $V_{DS}=15V,$ $V_{GS} = 4.5V$
Q_{gs}	Gate-to-Source charge	—	6	—		
Q_{gd}	Gate-to-Drain("Miller") charge	—	4	—		
$t_{d(on)}$	Turn-on delay time	—	8	—	ns	$V_{GS}=10V, V_{DS}=15V,$ $R_{GEN}=3\Omega$ $I_D = 20A$
t_r	Rise time	—	20	—		
$t_{d(off)}$	Turn-Off delay time	—	22	—		
t_f	Fall time	—	5	—		
C_{iss}	Input capacitance	—	1480	—	pF	$V_{GS} = 0V$ $V_{DS} = 15V$ $f = 1MHz$
C_{oss}	Output capacitance	—	560	—		
C_{riss}	Reverse transfer capacitance	—	70	—		

Source-Drain Ratings and Characteristics

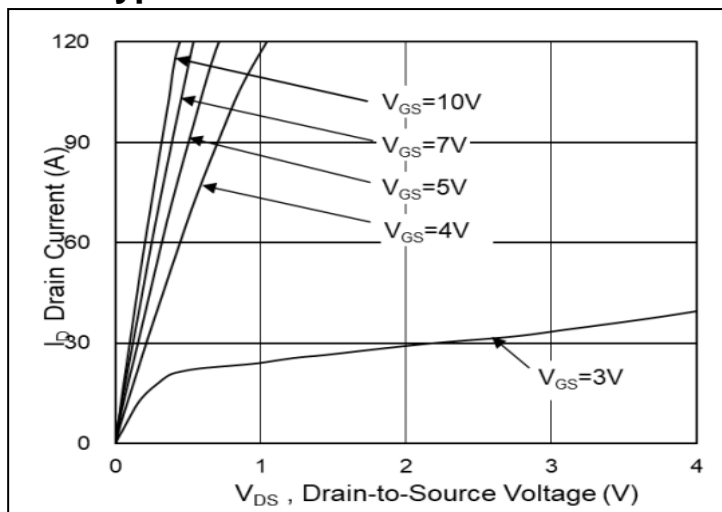
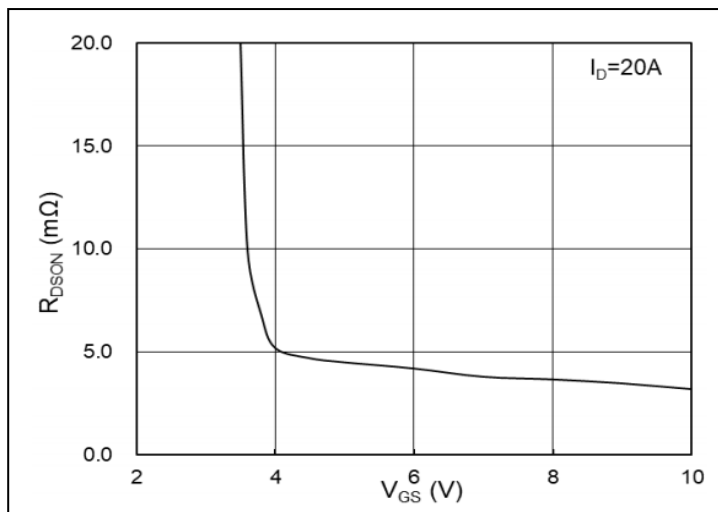
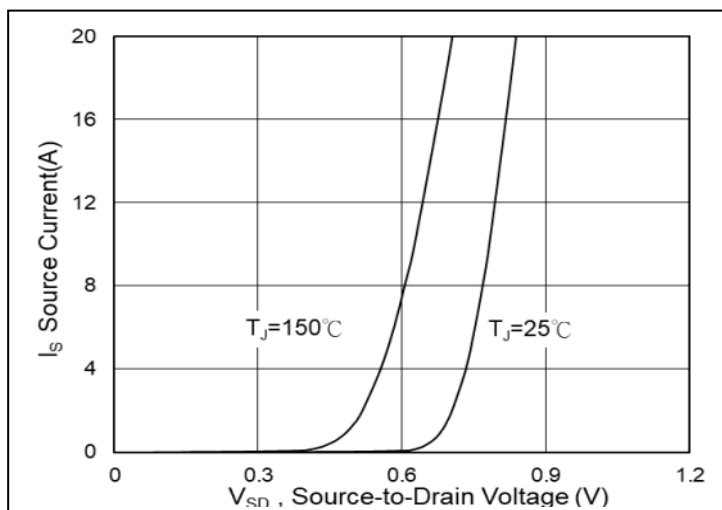
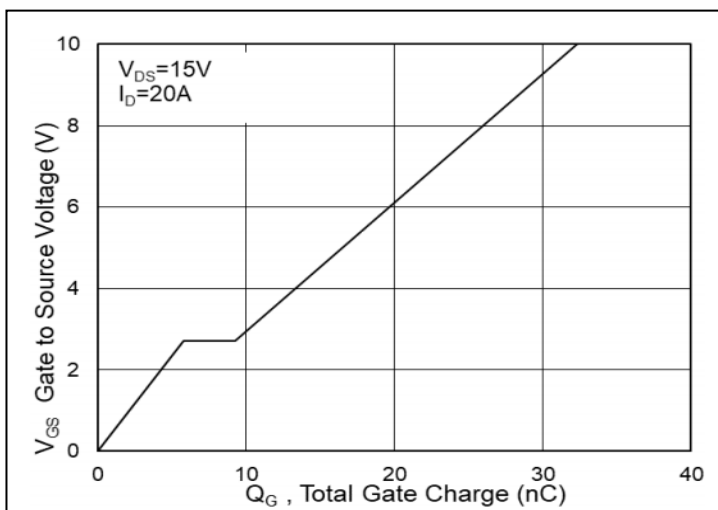
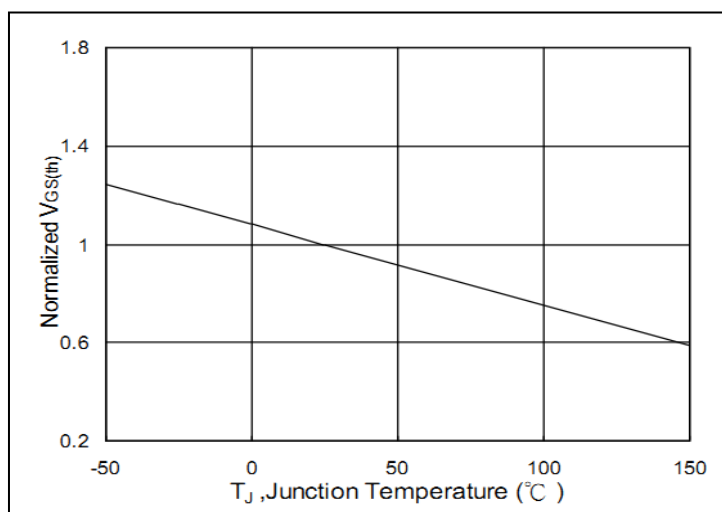
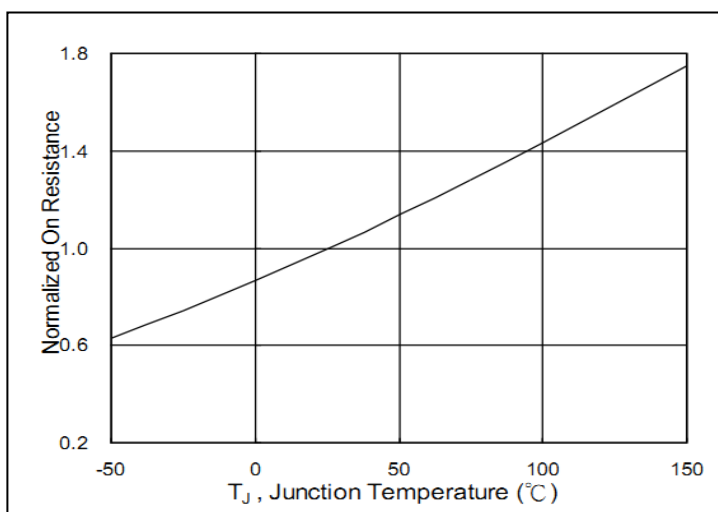
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	30	A	MOSFET symbol showing the integral reverse p-n junction diode. 
V_{SD}	Diode Forward Voltage	—	—	1	V	$I_S=1A, V_{GS}=0V$

Test circuits and Waveforms

EAS Test Circuit:

Gate charge test circuit:

Switching Time Test Circuit:

Switching Waveforms:


Notes:

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$

Typical electrical and thermal characteristics

Figure 1: Typical Output Characteristics

Figure 2: On-Resistance Vs. G-S Voltage

Figure 3: Source Drain Forward Characteristics

Figure 4: Gate Charge

Figure 5: Gate to source cut-off voltage

Figure 6: Normalized On-Resistance Vs. Case Temperature

Typical electrical and thermal characteristics

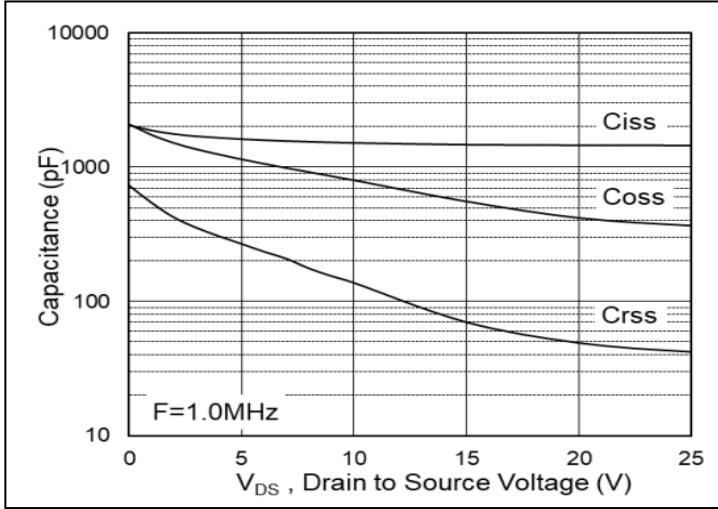


Figure 7: Capacitance

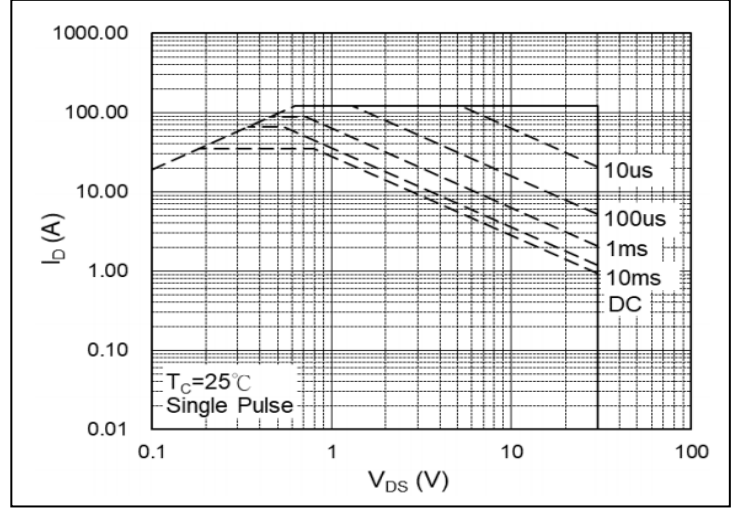


Figure 8: Safe Operation Area

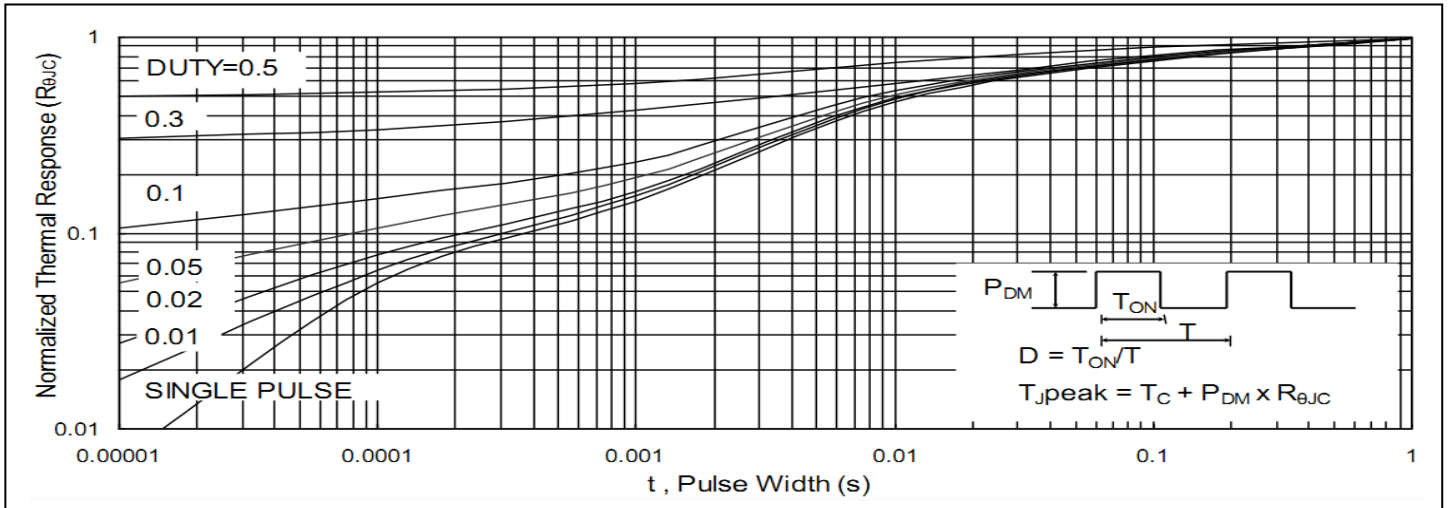
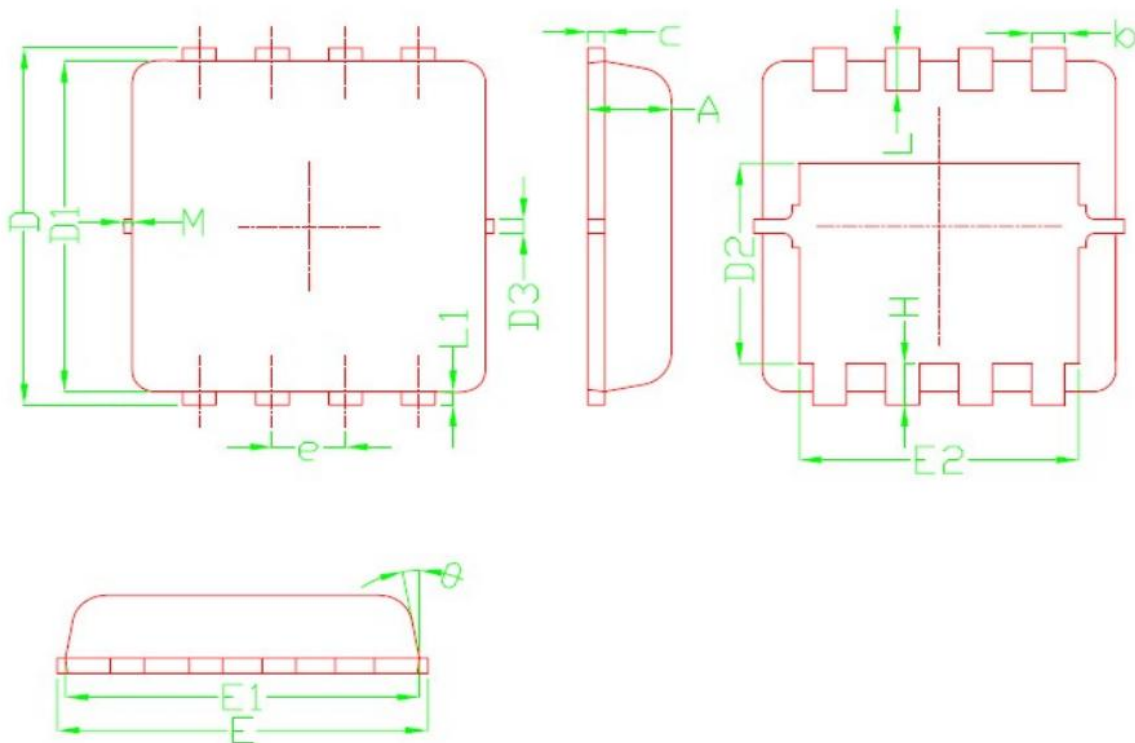


Figure 9: Transient Thermal Impedance

Mechanical Data:


SYMBOLS	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	0.70	0.85	0.027	0.034
b	0.20	0.40	0.007	0.016
c	0.10	0.25	0.004	0.010
D	3.15	3.45	0.124	0.136
D1	2.90	3.20	0.114	0.126
D2	1.54	1.98	0.060	0.080
D3	0.10	0.30	0.004	0.012
E	3.15	3.45	0.124	0.136
E1	3.00	3.25	0.118	0.128
E2	2.29	2.65	0.090	0.104
e	0.65 BSC		0.025 BSC	
H	0.28	0.65	0.011	0.026
θ	0°	14°	0°	14°
L	0.30	0.50	0.012	0.020
L1	0.13		0.005	
M	---	0.15	---	0.006

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